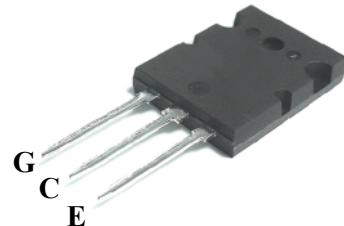
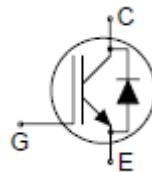


PRELIMINARY DATASHEET

**1200V 75A IGBT with anti-parallel diode,
in TO264 Package**

- Ultra low loss thin IGBT die
- Highly rugged SPT+ design
- Large bondable emitter area



MAXIMUM RATINGS

| Parameter | Symbol | Value | Units |
|---|-------------------|-------------|------------------|
| Collector-emitter voltage | V_{CE} | 1200 | V |
| DC collector current, limited by T_{jmax} $T_C = 100^\circ\text{C}$ | I_C | 75 | |
| Peak collector current | I_{CM} | 150 | A |
| Diode forward current $T_C = 100^\circ\text{C}$ | I_F | 60 | |
| Gate-emitter voltage | V_{GE} | ± 20 | V |
| Short circuit withstand time ¹ $V_{GE} = 15\text{V}$, $V_{CC} \leq 400\text{V}$, $T_j \leq 150^\circ\text{C}$ | t_{sc} | 10 | μs |
| Operating junction and storage temperature | T_j , T_{stg} | -40... +150 | $^\circ\text{C}$ |

Thermal Resistance

| Parameter | Symbol | Max. Value | Units |
|--|-------------|------------|-------|
| Characteristics | | | |
| IGBT thermal resistance, junction to case | R_{thJC} | 0.26 | |
| Diode thermal resistance, junction to case | R_{thJCD} | 0.4 | K/W |
| Thermal resistance, junction to ambient | R_{thJA} | 40 | |

¹ Allowed number of short circuits: < 1000; time between short circuits: > 1s.

ELECTRICAL CHARACTERISTICS, at $T_j = 25^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Value | | | Unit |
|--------------------------------------|----------------------|--|-------|------|-----------|---------------|
| | | | Min. | Typ. | Max. | |
| Static Characteristics | | | | | | |
| Collector-emitter breakdown voltage | $V_{(BR)CES}$ | $V_{GE} = 0\text{V}$, $I_C = 1\text{mA}$ | 1200 | - | - | |
| Collector-emitter saturation voltage | $V_{CE(\text{sat})}$ | $V_{GE} = 15\text{V}$, $I_C = 75\text{A}$ | - | 1.8 | - | |
| Diode forward voltage | V_F | $V_{GE} = 0\text{V}$, $I_F = 60\text{A}$ | - | 1.85 | - | |
| Gate-emitter threshold voltage | $V_{GE(\text{th})}$ | $I_C = 3\text{mA}$, $V_{CE} = V_{GE}$ | 5.0 | 6.2 | 7 | |
| Zero gate voltage collector current | I_{CES} | $V_{CE} = 1200\text{V}$, $V_{GE} = V_{CE}$ | - | - | 100 | μA |
| Diode reverse leakage current | I_R | $V_R = 1200\text{V}$ | - | - | - | |
| Gate-emitter leakage current | I_{GES} | $V_{CE} = 0\text{V}$, $V_{GE} = 20\text{V}$ | - | - | ± 200 | nA |
| Integrated gate resistor | R_{Gint} | | - | 3 | - | Ω |
| Dynamic Characteristics | | | | | | |
| Input capacitance | C_{iss} | $V_{CE} = 25\text{V}$, $V_{GE} = 0\text{V}$, $f = 1\text{MHz}$ | - | 5520 | - | pF |
| Output capacitance | C_{oss} | | - | 400 | - | |
| Reverse transfer capacitance | C_{rss} | | - | 260 | - | |

CAUTION: These devices are ESD sensitive. Use proper handling procedure.

SWITCHING CHARACTERISTICS, Inductive Load at $T_j = 25^\circ\text{C}$

| Parameter | Symbol | Conditions | Value | | | Unit |
|-----------------------------|--------------|--|-------|------|------|------|
| | | | Min. | Typ. | Max. | |
| IGBT Characteristics | | | | | | |
| Turn-on delay time | $t_{d(on)}$ | $V_{CC}=600\text{V}$, $I_C=75\text{A}$, $V_{GE}=\pm 15\text{V}$, $R_G=15\Omega$, $L_o = 60\text{nH}$, Inductive load. | - | 165 | - | ns |
| Rise time | t_r | | - | 75 | - | |
| Turn-off delay time | $t_{d(off)}$ | | - | 435 | - | |
| Fall time | t_f | | - | 50 | - | mJ |
| Turn-on energy | E_{on} | | - | 9.3 | - | |
| Turn-off energy | E_{off} | | - | 4.5 | - | |

Anti-Parallel Diode Characteristics

| | | | | | | |
|-------------------------------------|-----------|---|---|-----|---|---------------|
| Diode reverse recovery time | t_{rr} | $V_R=600\text{V}$, $I_F=60\text{A}$ $dI_F/dt = 1600\text{A}/\mu\text{s}$ $L_o = 60\text{nH}$, Inductive load | - | 250 | - | ns |
| Diode reverse recovery charge | Q_{rr} | | - | 10 | - | μC |
| Diode peak reverse recovery current | I_{rrm} | | - | 65 | - | A |

Package Outline Drawing
